

1450.4 meeting minutes – 07/10/13

Attendees: Ernie Wahl, Jim O'Reilly, Mitsuo Fujii, Markus Seuring

Not present: Julia DiChiaro, Oleg Erlich, Ajay Khoche, Paul Reuter

Summary:

No meeting on Wed., July 3.

Line numbers are from syntax document dated July 09, 2013.

- Line 843: ACCEPT: drop syntax with braces "Chip CHIP_NAME { (Site SITE_NR (, SITE_NR)*;) }". Allow repeat of same chip id "Chip CHIP_NAME;", ChannelMap CHAN_ID has to correspond
- Line 845: ACCEPT: Device/Package section: drop PkgNr statement.
 - Rationale:
 - syntax location is wrong: tester A may do package multi-site test, tester B single site
 - multi-site package test can be served via Device/Tester/TestHead/Partition/Sites section
- Line 850: ACCEPT: move PinMap below Signals and SignalGroups to allow open package pin mapping.
- Line 859: ACCEPT: definition: SITE_NR means device site number, i.e., chip site number at wafer test, package site number at package test.
- Line 865 - 866: ACCEPT: Device/Tester/TestHead/Partition/Sites/ChannelMap: change GRP_NAME to SIG_NAME and use optional brace syntax to group CHAN_IDs by package site. This works for multi-chip package also.
- Line 3993: reinstitute optional PAD_NAME, CAVEAT: buf_attribute Node NODE_NAME redundancy

Reference documents (If logged into your google account, can edit. If not, can only view.)

- <http://spreadsheets.google.com/ccc?key=0AoKiPr1I9LY9dF95dkhSTVVqOU5GbWJyWFNhY0JPX0E&hl=en>
- Namespace resolution examples document: <http://docs.google.com/Doc?docid=0AYKiPr1I9LY9ZGY4dmNjNTNfMGZkOGJ2bmZy&hl=en>
- Scratchpad spreadsheet: <https://spreadsheets0.google.com/ccc?key=tQ93VDnAZ-Cl9RFKpPrPDzw&authkey=COzyro8K&hl=en&authkey=COzyro8K#gid=0>
- Scratchpad "Word" doc: https://docs1.google.com/document/d/1zVu2M8nTJsrn0nFbBhiuM8-YRt4ErYqdy_uSa3x3_T4/edit?authkey=CLrgwrsG#

Next meeting: 07/17/1

For reference STIL .4 information can be found at the IEEE STIL website: <http://grouper.ieee.org/groups/1450/> (select the [P1450.4](#) link from the table) or use the direct link <http://grouper.ieee.org/groups/1450/dot4/index.html>